



UNIVERSITY OF MICHIGAN
COLLEGE OF ENGINEERING
THE RADIATION LABORATORY
DEPARTMENT OF ELECTRICAL ENGINEERING
AND COMPUTER SCIENCE

3228 EECS BUILDING
1301 BEAL AVENUE
ANN ARBOR, MICHIGAN 48109-2122
734 764-0500 FAX 734 647-2106
<http://www.eecs.umich.edu/RADLAB/>

Re: New Filing / Class II Permissive Change
FCC ID: DE4-3301TB
IC: 2998A-3301T

REQUEST FOR CONFIDENTIALITY

Pursuant to 47 CFR 0.457 (d) and 0.459 and IC RSP-100, Section 10, Thomas & Betts requests that a part of the subject application be held confidential. Thomas & Betts has spent substantial effort in developing this product and it is one of the first of its kind in industry. Having the subject information easily available to "competition" would negate the advantage they have achieved by developing this product. Not protecting the details of the design will result in financial hardship.

Type of Confidentiality Requested		Exhibit
☐ Short Term	☐ Permanent	(1) ID Label & Location
☐ Short Term	☐ Permanent	(3) External Photos
☐ Short Term	☒ Permanent	(4) Block Diagram
☐ Short Term	☒ Permanent	(5) Schematics
☐ Short Term	☐ Permanent	(7) Test Setup Photos
☐ Short Term	☐ Permanent	(8) User's Manual
☐ Short Term	☐ Permanent	(9) Internal Photos
☐ Short Term	☒ Permanent	(10) Parts List & Placement
☐ Short Term	☐ Permanent	(11) RF Exposure
☐ Short Term	☐ Permanent	(12) Description of Operation
1. Block diagram exhibit contains device crystal information the manufacturer considers to be proprietary information.		

Permanent Confidentiality:

Thomas & Betts requests the exhibits listed above as permanently confidential be permanently withheld from public review.

Short-Term Confidentiality:

Thomas & Betts requests the exhibits selected above as short term confidential be withheld from public view for a period of 45 days from the date of the Grant of Equipment Authorization and prior to marketing.

If there are any questions regarding this request, please contact me at the above address or call 734-483-4211, fax 734-647-2106 or e-mail liepa@umich.edu.

Sincerely,

Valdis V. Liepa, Research Scientist
University of Michigan